

- **EPIC™** (Enhanced-Performance Implanted CMOS) Submicron Process
- **ESD Protection Exceeds 2000 V Per MIL-STD-883, Method 3015; Exceeds 200 V Using Machine Model (C = 200 pF, R = 0)**
- **Latch-Up Performance Exceeds 250 mA Per JESD 17**
- **Typical V_{OLP} (Output Ground Bounce) < 0.8 V at $V_{CC} = 3.3$ V, $T_A = 25^\circ\text{C}$**
- **Typical V_{OHV} (Output V_{OH} Undershoot) > 2 V at $V_{CC} = 3.3$ V, $T_A = 25^\circ\text{C}$**
- **Inputs Accept Voltages to 5.5 V**
- **Package Options Include Plastic Small-Outline (D), Shrink Small-Outline (DB), Thin Very Small-Outline (DGV), and Thin Shrink Small-Outline (PW) Packages, Ceramic Flat (W) Package, Ceramic Chip Carriers (FK), and DIPs (J)**

description

The SN54LVC86A quadruple 2-input exclusive-OR gate is designed for 2.7-V to 3.6-V V_{CC} operation and the SN74LVC86A quadruple 2-input exclusive-OR gate is designed for 1.65-V to 3.6-V V_{CC} operation.

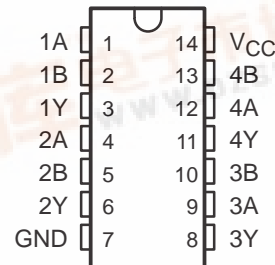
The 'LVC86A devices perform the Boolean function $Y = A \oplus B$ or $Y = \overline{A}B + A\overline{B}$ in positive logic.

A common application is as a true/complement element. If one of the inputs is low, the other input is reproduced in true form at the output. If one of the inputs is high, the signal on the other input is reproduced inverted at the output.

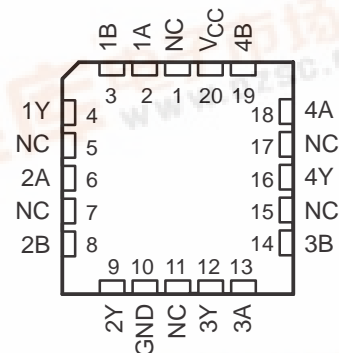
Inputs can be driven from either 3.3-V or 5-V devices. This feature allows the use of these devices as translators in a mixed 3.3-V/5-V system environment.

The SN54LVC86A is characterized for operation over the full military temperature range of -55°C to 125°C . The SN74LVC86A is characterized for operation from -40°C to 85°C .

SN54LVC86A ... J OR W PACKAGE
SN74LVC86A ... D, DB, DGV, OR PW PACKAGE
(TOP VIEW)



SN54LVC86A ... FK PACKAGE
(TOP VIEW)



NC – No internal connection

FUNCTION TABLE
(each gate)

INPUTS		OUTPUT
A	B	Y
L	L	L
L	H	H
H	L	H
H	H	L

Please be aware that an important notice concerning availability, standard warranty, and use in critical applications of Texas Instruments semiconductor products and disclaimers thereto appears at the end of this data sheet.

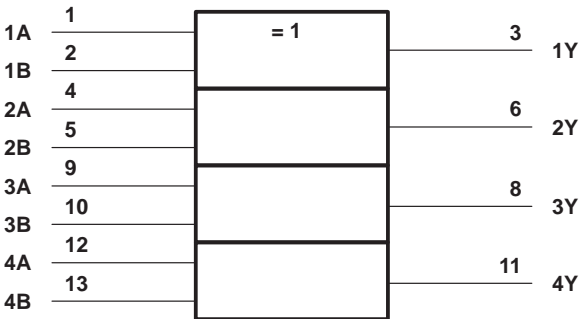
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SN54LVC86A, SN74LVC86A QUADRUPLE 2-INPUT EXCLUSIVE-OR GATES

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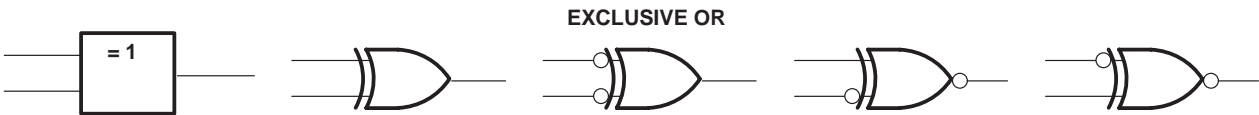
logic symbol†



† This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12. Pin numbers shown are for the D, DB, DGV, J, PW, and W packages.

exclusive-OR logic

An exclusive-OR gate has many applications, some of which can be represented better by alternative logic symbols.



These five equivalent exclusive-OR symbols are valid for an SN74LVC86A gate in positive logic; negation may be shown at any two ports.

LOGIC-IDENTITY ELEMENT



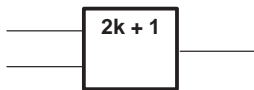
The output is active (low) if all inputs stand at the same logic level (i.e., A = B).

EVEN-PARITY ELEMENT



The output is active (low) if an even number of inputs (i.e., 0 or 2) are active.

ODD-PARITY ELEMENT



The output is active (high) if an odd number of inputs (i.e., only 1 of the 2) are active.

absolute maximum ratings over operating free-air temperature range (unless otherwise noted)‡

Supply voltage range, V_{CC}	–0.5 V to 6.5 V
Input voltage range, V_I (see Note 1)	–0.5 V to 6.5 V
Output voltage range, V_O (see Notes 1 and 2)	–0.5 V to $V_{CC} + 0.5$ V
Input clamp current, I_{IK} ($V_I < 0$)	–50 mA
Output clamp current, I_{OK} ($V_O < 0$)	–50 mA
Continuous output current, I_O	±50 mA
Continuous current through V_{CC} or GND	±100 mA
Package thermal impedance, θ_{JA} (see Note 3):	
D package	127°C/W
DB package	158°C/W
DGV package	182°C/W
PW package	170°C/W
Storage temperature range, T_{stg}	–65°C to 150°C

‡ Stresses beyond those listed under “absolute maximum ratings” may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under “recommended operating conditions” is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTES: 1. The input negative-voltage and output voltage ratings may be exceeded if the input and output current ratings are observed.
2. The value of V_{CC} is provided in the recommended operating conditions table.
3. The package thermal impedance is calculated in accordance with JESD 51.

SN54LVC86A, SN74LVC86A QUADRUPLE 2-INPUT EXCLUSIVE-OR GATES

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recommended operating conditions (see Note 4)

			SN54LVC86A		SN74LVC86A		UNIT
			MIN	MAX	MIN	MAX	
V _{CC}	Supply voltage	Operating	2	3.6	1.65	3.6	V
		Data retention only	1.5		1.5		
V _{IH}	High-level input voltage	V _{CC} = 1.65 V to 1.95 V			0.65 × V _{CC}		V
		V _{CC} = 2.3 V to 2.7 V			1.7		
		V _{CC} = 2.7 V to 3.6 V	2		2		
V _{IL}	Low-level input voltage	V _{CC} = 1.65 V to 1.95 V			0.35 × V _{CC}		V
		V _{CC} = 2.3 V to 2.7 V			0.7		
		V _{CC} = 2.7 V to 3.6 V	0.8		0.8		
V _I	Input voltage		0	5.5	0	5.5	V
V _O	Output voltage		0	V _{CC}	0	V _{CC}	V
I _{OH}	High-level output current	V _{CC} = 1.65 V			−4		mA
		V _{CC} = 2.3 V			−8		
		V _{CC} = 2.7 V	−12		−12		
		V _{CC} = 3 V	−24		−24		
I _{OL}	Low-level output current	V _{CC} = 1.65 V			4		mA
		V _{CC} = 2.3 V			8		
		V _{CC} = 2.7 V	12		12		
		V _{CC} = 3 V	24		24		
Δt/Δv	Input transition rise or fall rate		0	9	0	9	ns/V
T _A	Operating free-air temperature		−55	125	−40	85	°C

NOTE 4: All unused inputs of the device must be held at V_{CC} or GND to ensure proper device operation. Refer to the TI application report, *Implications of Slow or Floating CMOS Inputs*, literature number SCBA004.

SN54LVC86A, SN74LVC86A

QUADRUPLE 2-INPUT EXCLUSIVE-OR GATES

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electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS	V _{CC}	SN54LVC86A			SN74LVC86A			UNIT
			MIN	TYP†	MAX	MIN	TYP†	MAX	
V _{OH}	I _{OH} = –100 μA	1.65 V to 3.6 V				V _{CC} –0.2			V
		2.7 V to 3.6 V	V _{CC} –0.2						
	I _{OH} = –4 mA	1.65 V				1.2			
	I _{OH} = –8 mA	2.3 V				1.7			
	I _{OH} = –12 mA	2.7 V		2.2		2.2			
		3 V		2.4		2.4			
	I _{OH} = –24 mA	3 V		2.2		2.2			
V _{OL}	I _{OL} = 100 μA	1.65 V to 3.6 V				0.2			V
		2.7 V to 3.6 V	0.2						
	I _{OL} = 4 mA	1.65 V				0.45			
	I _{OL} = 8 mA	2.3 V				0.7			
	I _{OL} = 12 mA	2.7 V		0.4		0.4			
	I _{OL} = 24 mA	3 V		0.55		0.55			
I _I	V _I = 5.5 V or GND	3.6 V	±5			±5			μA
I _{CC}	V _I = V _{CC} or GND, I _O = 0	3.6 V	10			10			μA
ΔI _{CC}	One input at V _{CC} – 0.6 V, Other inputs at V _{CC} or GND	2.7 V to 3.6 V	500			500			μA
C _i	V _I = V _{CC} or GND	3.3 V	5			5			pF

† All typical values are at V_{CC} = 3.3 V, T_A = 25°C.

switching characteristics over recommended operating free-air temperature range (unless otherwise noted) (see Figure 3)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	SN54LVC86A				UNIT
			V _{CC} = 2.7 V		V _{CC} = 3.3 V ± 0.3 V		
			MIN	MAX	MIN	MAX	
t _{pd}	A	Y	5.6		1	4.6	ns

switching characteristics over recommended operating free-air temperature range (unless otherwise noted) (see Figures 1 through 3)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	SN74LVC86A						UNIT		
			V _{CC} = 1.8 V		V _{CC} = 2.5 V ± 0.2 V		V _{CC} = 2.7 V			V _{CC} = 3.3 V ± 0.3 V	
			TYP		MIN	MAX	MIN	MAX		MIN	MAX
t _{pd}	A	Y	13.6		1	7.6		5.6	1	4.6	ns
t _{sk(o)} [‡]									1		ns

‡ Skew between any two outputs of the same package switching in the same direction

operating characteristics, T_A = 25°C

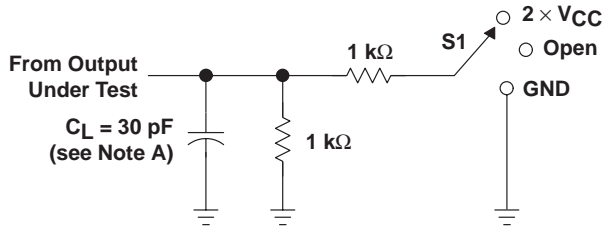
PARAMETER		TEST CONDITIONS	V _{CC} = 1.8 V	V _{CC} = 2.5 V	V _{CC} = 3.3 V	UNIT
			TYP	TYP	TYP	
C _{pd}	Power dissipation capacitance per gate	f = 10 MHz	6.5	7.5	8.5	pF

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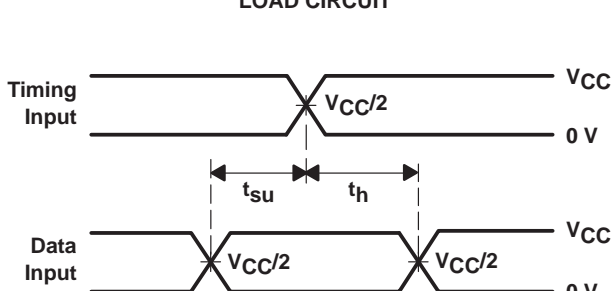
PARAMETER MEASUREMENT INFORMATION

$$V_{CC} = 1.8 \text{ V} \pm 0.15 \text{ V}$$

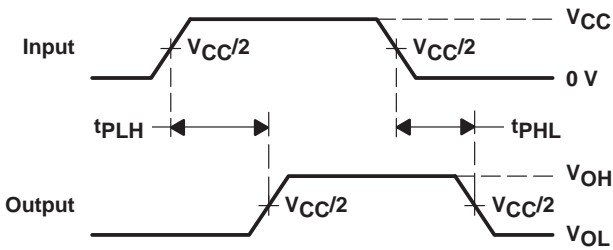


LOAD CIRCUIT

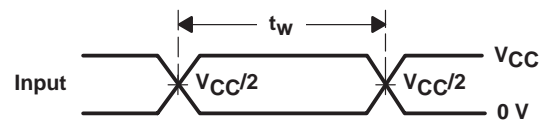
TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	2 \times V_{CC}
t_{PHZ}/t_{PZH}	Open



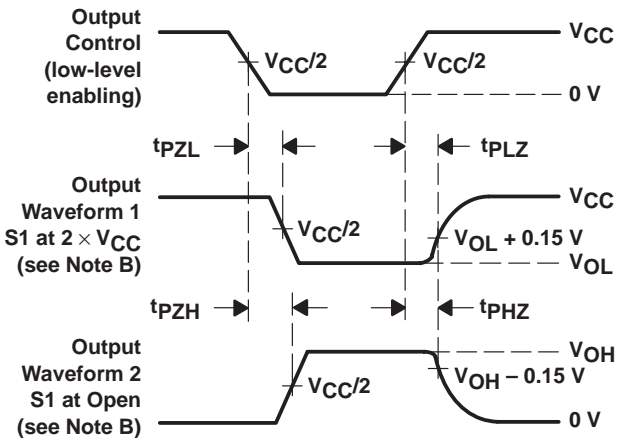
VOLTAGE WAVEFORMS
SETUP AND HOLD TIMES



VOLTAGE WAVEFORMS
PROPAGATION DELAY TIMES



VOLTAGE WAVEFORMS
PULSE DURATION



VOLTAGE WAVEFORMS
ENABLE AND DISABLE TIMES

- NOTES:
- C_L includes probe and jig capacitance.
 - Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - All input pulses are supplied by generators having the following characteristics: $PRR \leq 10 \text{ MHz}$, $Z_O = 50 \Omega$, $t_r \leq 2 \text{ ns}$, $t_f \leq 2 \text{ ns}$.
 - The outputs are measured one at a time with one transition per measurement.
 - t_{PLZ} and t_{PHZ} are the same as t_{dis} .
 - t_{PZL} and t_{PZH} are the same as t_{en} .
 - t_{PLH} and t_{PHL} are the same as t_{pd} .

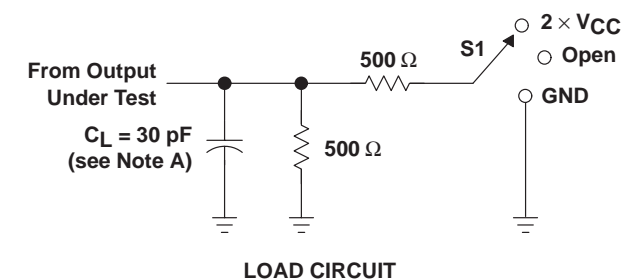
Figure 1. Load Circuit and Voltage Waveforms

SN54LVC86A, SN74LVC86A QUADRUPLE 2-INPUT EXCLUSIVE-OR GATES

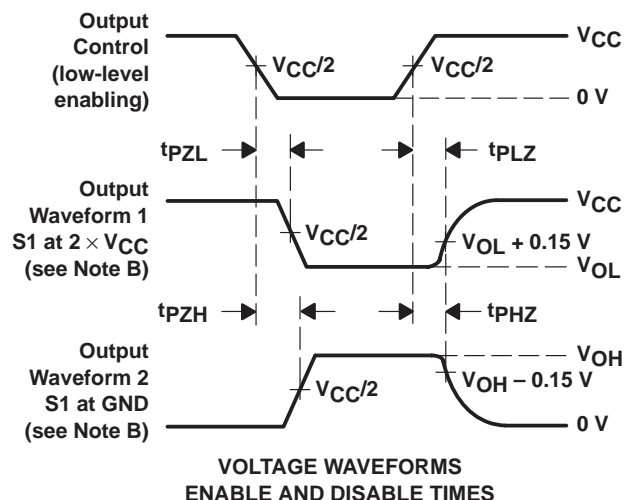
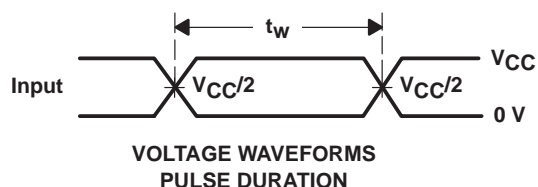
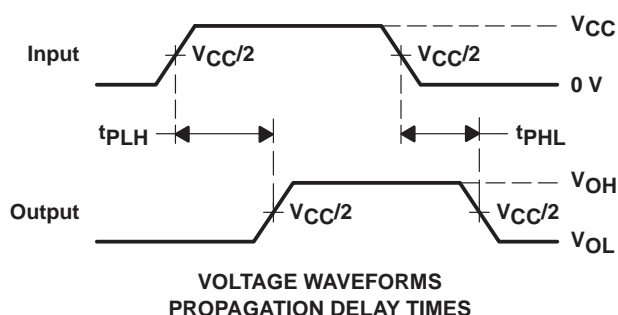
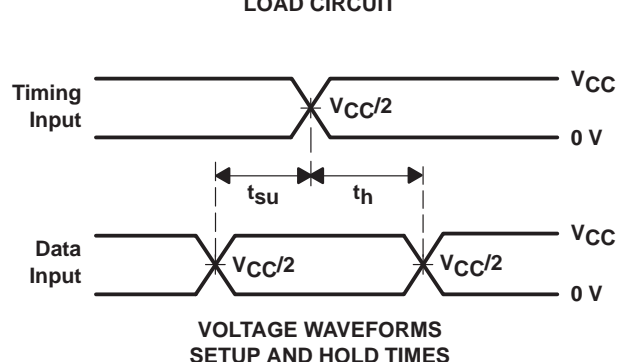
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PARAMETER MEASUREMENT INFORMATION

$$V_{CC} = 2.5 \text{ V} \pm 0.2 \text{ V}$$



TEST	S1
t_{pd} t_{PLZ}/t_{PZL} t_{PHZ}/t_{PZH}	Open 2 $\times V_{CC}$ GND



- NOTES:
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 - Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
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 - The outputs are measured one at a time with one transition per measurement.
 - t_{PLZ} and t_{PHZ} are the same as t_{dis} .
 - t_{PZL} and t_{PZH} are the same as t_{en} .
 - t_{PLH} and t_{PHL} are the same as t_{pd} .

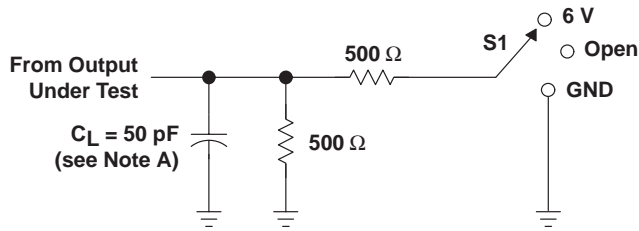
Figure 2. Load Circuit and Voltage Waveforms

SN54LVC86A, SN74LVC86A QUADRUPLE 2-INPUT EXCLUSIVE-OR GATES

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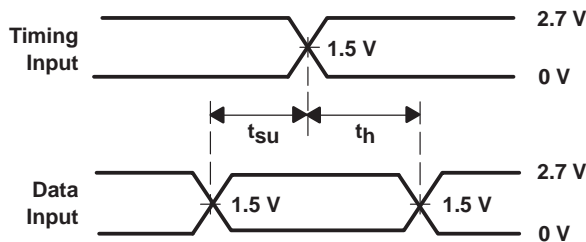
PARAMETER MEASUREMENT INFORMATION

$V_{CC} = 2.7 \text{ V AND } 3.3 \text{ V} \pm 0.3 \text{ V}$

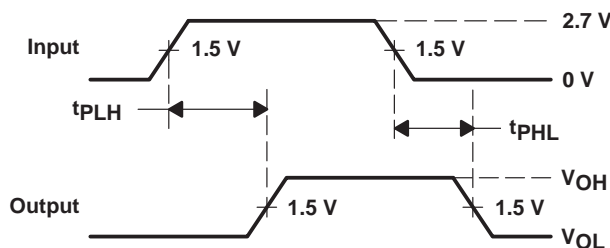


LOAD CIRCUIT

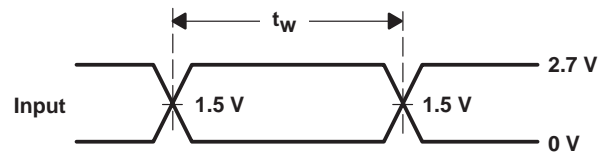
TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	6 V
t_{PHZ}/t_{PZH}	GND



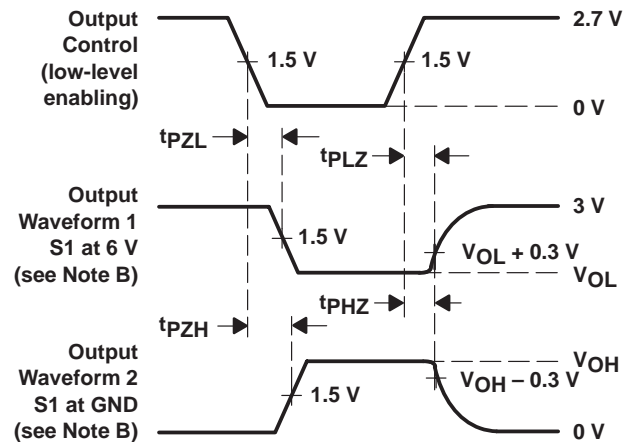
VOLTAGE WAVEFORMS
SETUP AND HOLD TIMES



VOLTAGE WAVEFORMS
PROPAGATION DELAY TIMES



VOLTAGE WAVEFORMS
PULSE DURATION



VOLTAGE WAVEFORMS
ENABLE AND DISABLE TIMES

- NOTES:
- A. C_L includes probe and jig capacitance.
 - B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - C. All input pulses are supplied by generators having the following characteristics: $PRR \leq 10 \text{ MHz}$, $Z_O = 50 \Omega$, $t_r \leq 2.5 \text{ ns}$, $t_f \leq 2.5 \text{ ns}$.
 - D. The outputs are measured one at a time with one transition per measurement.
 - E. t_{PLZ} and t_{PHZ} are the same as t_{dis} .
 - F. t_{PZL} and t_{PZH} are the same as t_{en} .
 - G. t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 3. Load Circuit and Voltage Waveforms

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